

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	15368	(three adj dimension\$2 or 3D) and (ball adj grid adj array or BGA or lead\$2 or terminals)and inspect\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/04 15:56
L2	1	1 and ((captur\$3 or obtain\$3)near3 pluralit\$3 adj views and(front or back or side or bottom))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/04 16:04
L3	0	1 and single near3 camera with(two adj mirrors or two adj lenses or two adj optical adj elements)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/04 16:06
L4	0	2 and single near3 camera with(two adj mirrors or two adj lenses or two adj optical adj elements)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/04 16:06

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Example: acoustic imaging (means the phrase acoustic imaging plus any stem variations)
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Example: optical <and> (fiber <or> fibre) <in> ti
- 3) Limit the results by selecting Search Options.
- 4) Click Search. See [Search Examples](#)

 (three <near/5> dimensional
 or 3d) and (ball <near/5> adj
 grid <near/5> array or bga or
 lead\$2 or terminals)and
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Note: This function returns plural and suffixed forms of the keyword(s).

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